- Programmable Asynchronous Preset or Output Control
- Power-On Preset of All Flip-Flops
- 8-Bit Internal State Register With 4-Bit Output Register
- Power Dissipation . . . 600 mW Typical
- Functionally Equivalent to, but Faster Than 82S167A[†]

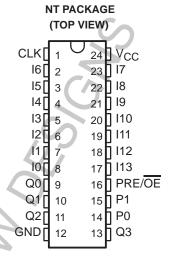
description

The TIB82S167BC is a TTL field-programmable state machine of the Mealy type. This state machine (logic sequencer) contains 48 product terms (AND terms) and 12 pairs of sum terms (OR terms). The product and sum terms are used to control the 8-bit internal state register and the 4-bit output register.

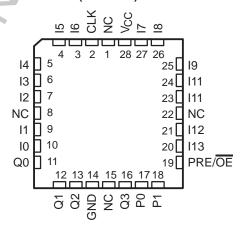
The outputs of the internal state register (P0-P7) are fed back and combined with the 14 inputs (I0-I13) to form the AND array. In addition the first two bits of the internal state register (P0-P1) are brought off-chip to allow the output register to be extended to 6 bits if desired. A single sum term is complemented and fed back to the AND array which allows any of the product terms .o be summed, complemented, and used as inputs to the AND array.

The state and output registers are positive edgetriggered S/R flip-flops. These registers are unconditionally preset high during power up. PRE/OE can be used as PRE in pueset both registers or, by blowing the proper fuse, be converted to an output control function, OE.

The TIB82S167BC is chara crited for operation from 0°C to 75°C.



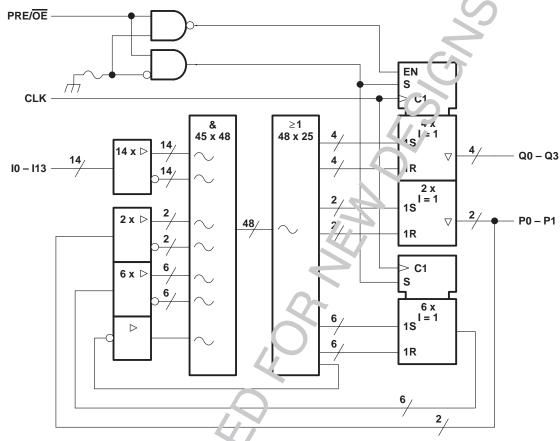
FN PACKAGE (TOP VIEW)



NC - No internal connection

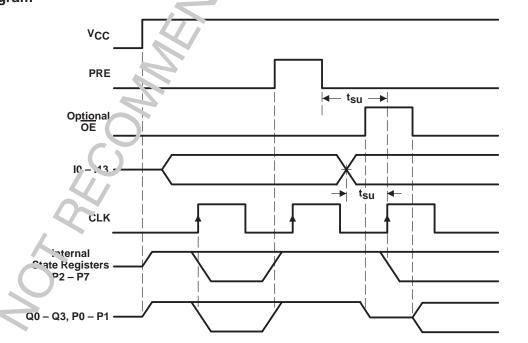
† Power-up preset and asynchronous preset functions are not identical to 82S167A.

functional block diagram (positive logic)

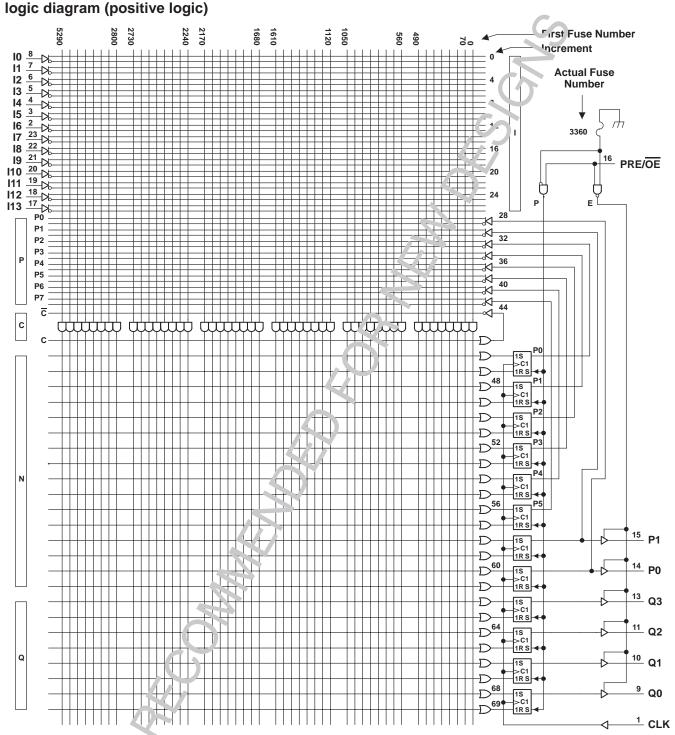


 \sim denotes fused inputs

timing diagram







- NOTES: 1. All AND gate inputs with a blown link float to the high level.
 - 2. All OR gat inputs with a blown link float to the low level.
 - 3. Fuse numbers = First fuse number + Increment



TIB82S167BC $14 \times 48 \times 6$ FIELD-PROGRAMMABLE LOGIC SEQUENCER WITH 3-STATE OUTPUTS OR PRESET

SRPS026A - D2896, JANUARY 1985 - REVISED NOVEMBBER 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 4)		7 V
Input voltage (see Note 4)	<u> </u>	.5 V
Voltage applied to disabled output (see Note 4)	5.	.5 V
Operating free-air temperature range	0°C to 75	5°C
Storage temperature range	65°C to 150	0°C

NOTE 4: These ratings apply except for programming pins during a programming cycle.

recommended operating conditions

			MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.75	5	5.25	V
VIH	High-level input voltage		2		5.5	V
V_{IL}	Low-level input voltage				0.8	V
IOH	High-level output current				-3.2	mA
loL	Low-level output current	4/1			24	mA
f	Clock fraguency t	1 thru 48 product tern. wn. out C-array ‡	0		50	MHz
^f clock	Clock frequency†	1 thru 48 product cris with C-array	0		30	1011 12
+	Pluse duration	Clock high or low	10			ns
τw	Fluse duration	Preset	15			113
+	Setup time before CLK↑,	Without C-array	15			ns
t _{su}	1 thru 48 product terms	With C-ar ay	30			113
t _{su}	Setup time, Preset low (inactive) before CLK↑§	7,0	8			ns
th	Hold time, input after CLK↑		0			ns
TA	Operating free-air temperature		0	25	75	°C

[†] The maximum clock frequency is independent of the internal programmed configuration. If an output is fed back externally to an input, the maximum clock frequency must be calculated.



[‡] The C-array is the single sum term that is complemented and led back to the AND array.

[§] After Preset goes inactive, normal clocking resumes on the irst low-to-high clock transition.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MnN	ı YP†	MAX	UNIT
VIK	V _{CC} = 4.75 V,	$I_{I} = -18 \text{ mA}$				-1.2	V
VOH	$V_{CC} = 4.75 V$,	$I_{OH} = -3.2 \text{ mA}$		7.4	3		V
VOL	$V_{CC} = 4.75 V$,	$I_{OL} = 24 \text{ mA}$			0.37	0.5	V
lozh	$V_{CC} = 5.25 \text{ V},$	V _O = 2.7 V	Ca			20	μΑ
lozL	$V_{CC} = 5.25 \text{ V},$	$V_0 = 0.4 V$				-20	μΑ
I _I	$V_{CC} = 5.25 \text{ V},$	V _I = 5.5 V	4/1			25	μΑ
lіН	$V_{CC} = 5.25 \text{ V},$	V _I = 2.7 V				20	μΑ
I _{IL}	$V_{CC} = 5.25 \text{ V},$	V _I = 0.4 V				-0.25	mA
10 [‡]	V _{CC} = 5.25 V,	V _O = 2.25 V		-30		-112	mA
Icc	V _{CC} <u>= 5</u> .25 V, PRE/OE at GND,	$V_I = 4.5 V$, Outputs open	7		90	160	mA

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITION	MIN	TYP [†]	MAX	UNIT
f _{max} §	Without	C array		50	70		MHz
imax	With C	array		30	45		IVIIIZ
t _{pd}	CLK↑	Q	R1 = 500Ω ,		10	15	ns
^t pd	PRE↑	Q	R2 = 500Ω ,		8	20	ns
^t pd	V _{CC} ↑	9	See Figure 5		0	10	ns
t _{en}	OE↓	2			10	20	ns
^t dis	ŌE↑	Q			5	10	ns

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

programming information

Texas Instruments Programmabl . Log.c Devices can be programmed using widely available software and inexpensive device programmers.

Complete programming specifications, algorithms, and the latest information on hardware, software, and firmware are available upon social struments. Information on programmers capable of programming Texas Instruments Programmable Logic is also evailable, upon request, from the nearest TI field sales office, local authorized TI distributor, or by calling Texas instruments at (214) 997-5666.

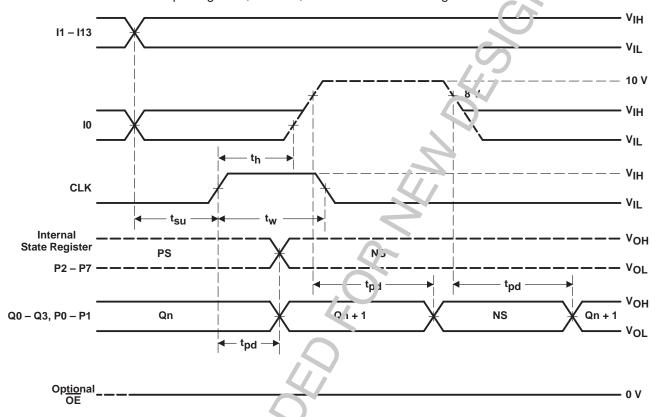


[‡] The output conditions hace been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

[§] f_{max} is independent of the internal programmed configuration, and the number of product terms used.

diagnostics

A diagnostics mode is provided with these devices that allows the user to inspect the contents of the state register. When I0 is held at 10 V, the state register bits P2-P7 will appear at the Q0-Q3 and P0-P1 outputs. The contents of the output registers, Q0-Q3, P0-P1 remain unchanged.



PS = Present State, NS = Next State

Figure 1. Diagnostic Waveforms



test array

A test array that consists of product lines 48 and 49 has been added to these devices 30 a low testing prior to programming. The test array is factory programmed as shown in Table 1. Testing is accomplished by connecting Q0-Q3 to I10-I13, PRE/OE to GND, and applying the proper input signals as shown in Figure 2. Product lines 48 and 49 must be deleted during user programming to avoid interference with the range ammed logic function.

OPTION PRE/OE Н AND OR PRESENT STATE NEXT STATE **INPUT** OUT **PRODUCT** (PS) (NS) (Qn) (In) LINE С c 3 2 1 10 15 5 4 3 5 4 4 3 8 0 48 Н нинн 49

Table 1. Test Array Program

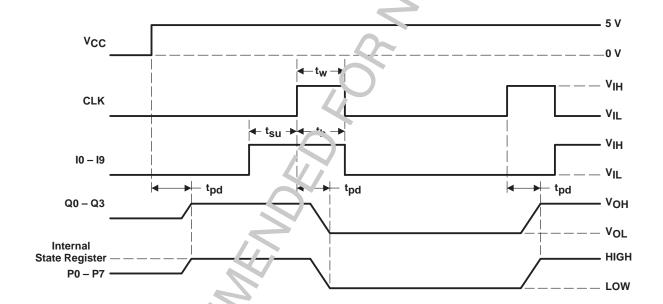


Figure 2. Test Array Waveforms

Table 2. Test Array Deleted

																												()PI	ΓΙΟ	N P	RE	/OE					Н
		AND														AND OR																						
PRODUCT LINE	С	c c 1 1 1 1 1 1 1								INPUT (In)								PRESENT STATE (PS)					NEXT STATE OUT (NS) (Qn)															
L	L	L	5	1	3	2	1	0	9	8	7	6	5	4	3	2	1	0	5	4	3	2	1	0	5	4	3	2	1	0	7	6	5	4	3	2	1	0
48	-	E	ĮŲ.	ĮΗ	H	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	_	_	_	_	-	-	_	_	_	-	-	-	_	_
49	-	X	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	L	_	-	-	-	-	-	-	-	-	-	-	-	-	_

X = Fuse intact se blown



TIB82S167B, 82S167A COMPARISON

The Texas Instruments TIB82S167B is a $14 \times 48 \times 6$ Field-Programmable Logic Sequencer that is functionally equivalent to the Signetics 82S167A. However, the TIB82S167B is designed for a maximum speed of 50 MHz with the preset function being made conventional. As a result the TIB82S167B differs from the 22S167A in speed and in the preset recovery function.

The TIB82S167B is a high-speed version of the original 82S167A. The TIB82S167D features increased switching speeds with no increase in power. The maximum operating frequency is increased from 20 MHz to 50 MHz and does not decrease as more product terms are connected to each sum (OR) line. For instance, if all 48 product terms were connected to a sum line on the original 82S167A, the f_{max} would be about 15 MHz. The f_{max} for the TIB82S167B remains at 50 MHz regardless of the programmed configuration. In addition, the preset recovery sequence was changed to a conventional recovery sequence, providing quicker clock recovery times. This is explained in the following paragraph.

The TIB82S167B and the 82S167A are equipped with power-up prese, and asynchronous preset functions. The power-up preset causes the registers to go high during power up. The asynchronous preset inhibits clocking and causes the registers to go high whenever the preset pin is taken high fifter a power-up preset occurs, the minimum setup time from power up to the first clock pulse must be met in order assure that clocking is not inhibited. In a similar manner after an asynchronous preset, the preset input must return ow (mactive) for a given time, t_{su}, before clocking.

The Signetics 82S167A was designed in such a way that aft or both power-up preset and asynchronous preset it requires that a high-to-low clock transition occur before a clocking transition (low-to-high) will be recognized. This is shown in Figure 3. The Texas Instruments TIB82S167B doe and require a high-to-low clock transition before clocking can be resumed, it only requires that the preset be inactive 8 ns (preset inactive-state setup time) before the clock rising edge. See Figure 4.

The TIB82S167B, with an f_{max} of 50 MHz, is ideal for systems in which the state machine must run several times faster than the system clock. It is recommended that the TIP32S167B be used in new designs. *However, if the TIB82S167B is used to replace the 82S167A, then the customer nust understand that clocking will begin with the first clock rising edge after preset.*

Table 3. Speed Differences

PARAMETER	82S167A SIGNETICS	TIB82S167B TI ONLY
ι _{1,} αχ	20 MHz	50 MHz
t _{pd} , CLi' ic Q	20 ns	15 ns



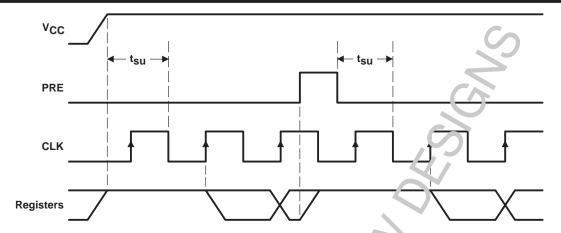


Figure 3. 82S167A Preset Recovery Overation

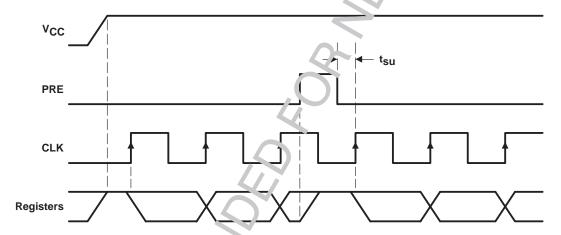
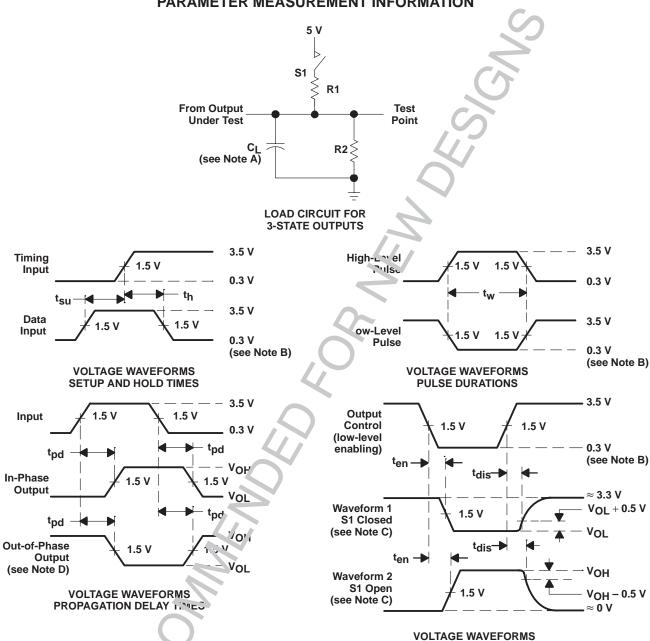


Figure 4. TIB32S167B Preset Recovery Operation



PARAMETER MEASUREMENT INFORMATION



- NOTES: A. CL includes probe and is 30 pF for total and ten, 5 pF for tdis.
 - B. All input pulses he refull in a following characteristics: $PRR \le 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
 - C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

- D. When measuring, ropagation delay times of 3-state outputs, switch S1 is closed.
- E. Equivalent 'bads may be used for testing.

Figure 5. Load Circuit and Voltage Waveforms



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